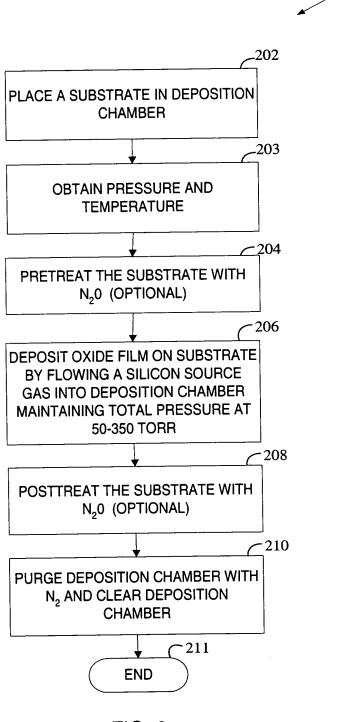


FIG. 1 (PRIOR ART)



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FIG. 2

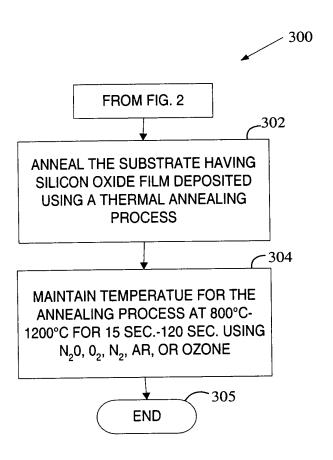


FIG. 3

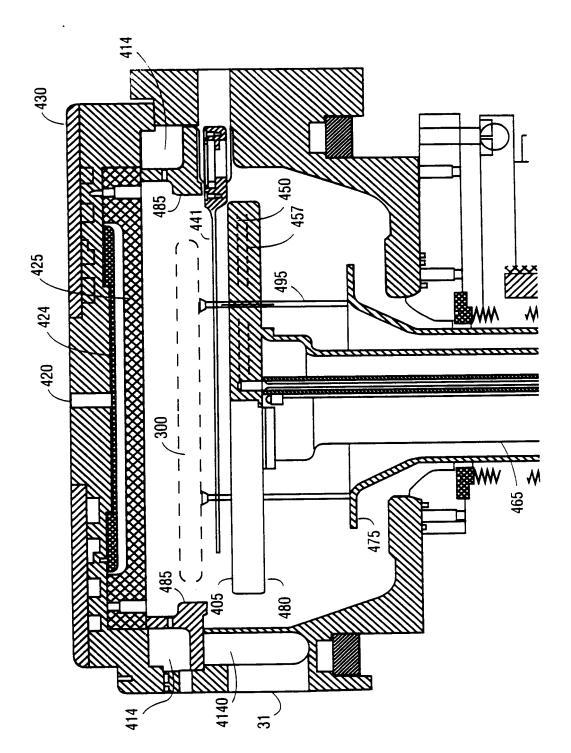


FIG. 5

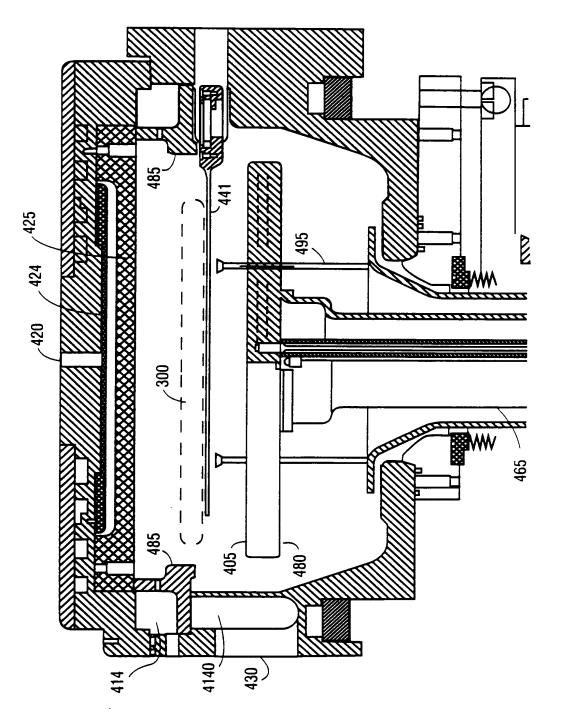


FIG. 6

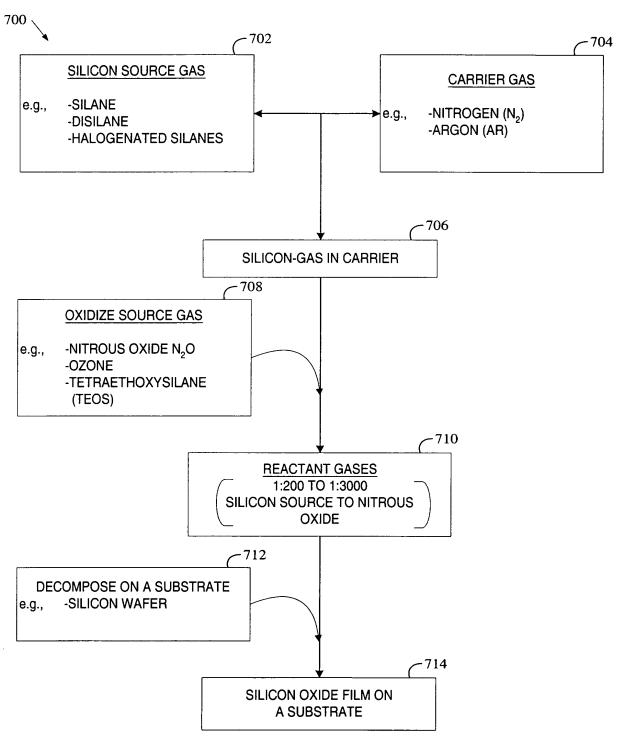


FIG. 7

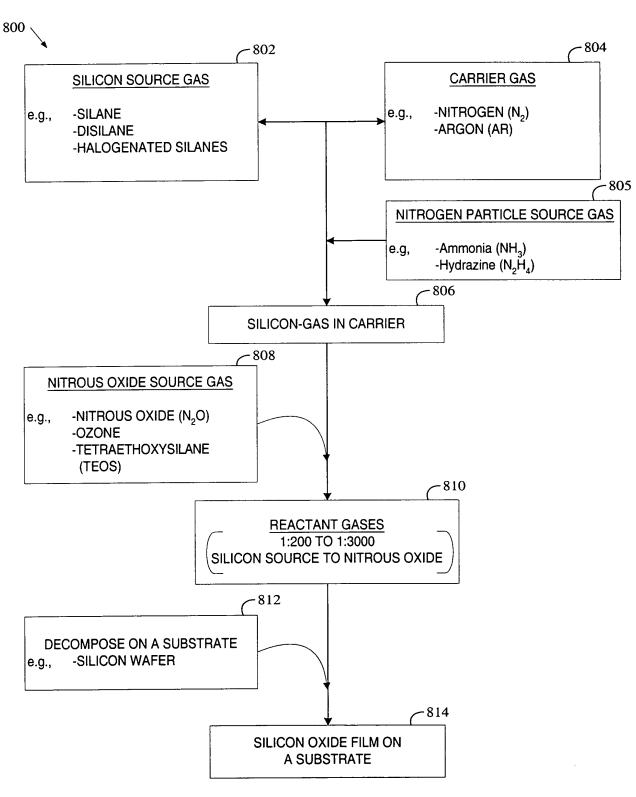
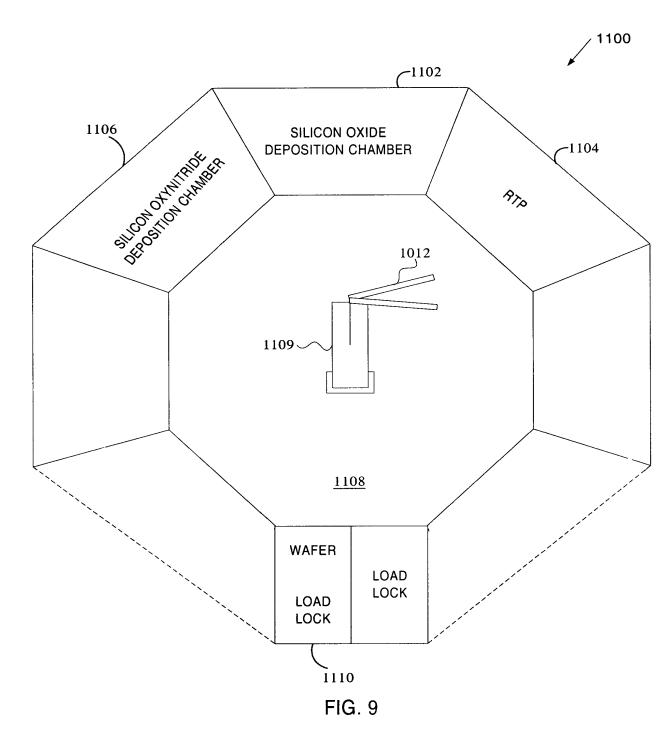
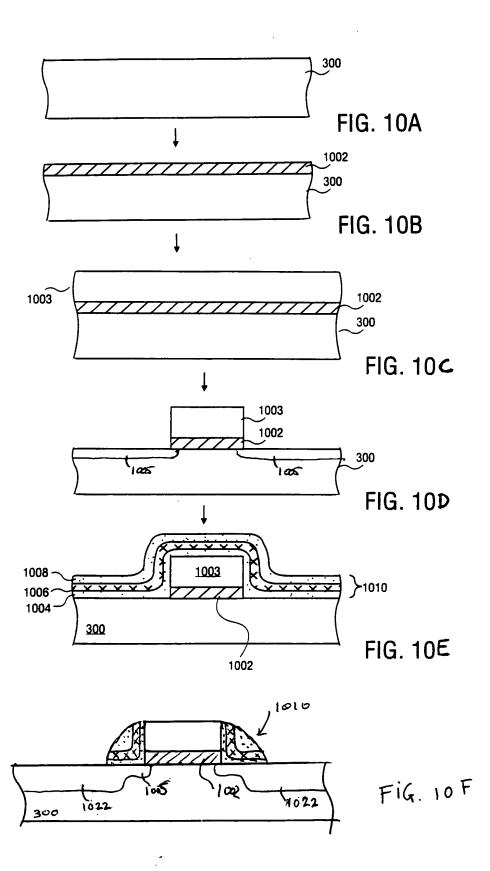
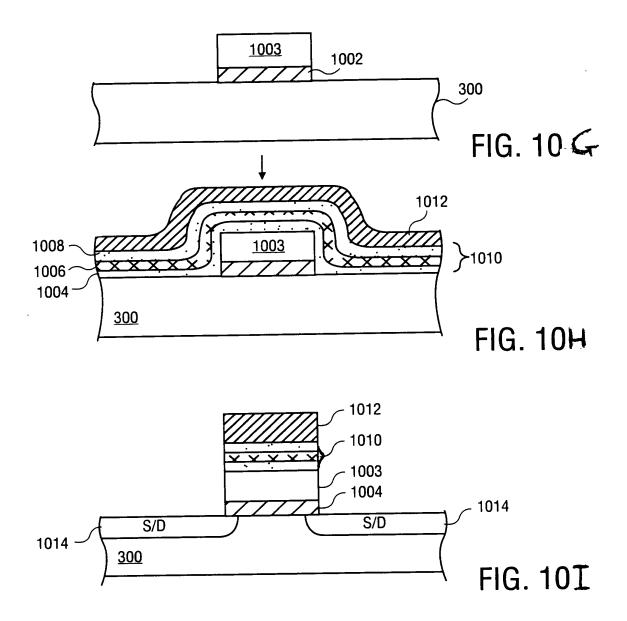


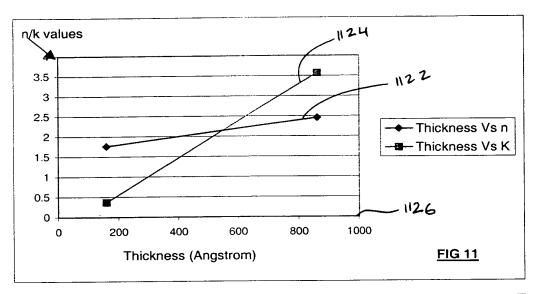
FIG. 8

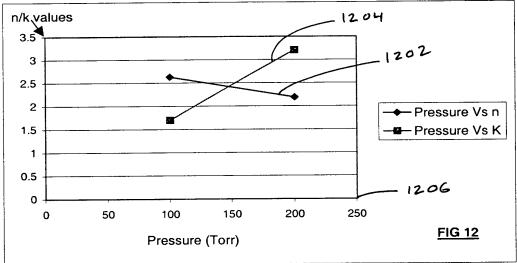


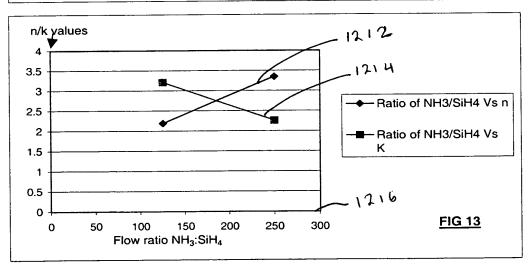




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Step Coverage vs N2O/SiH4 ratio

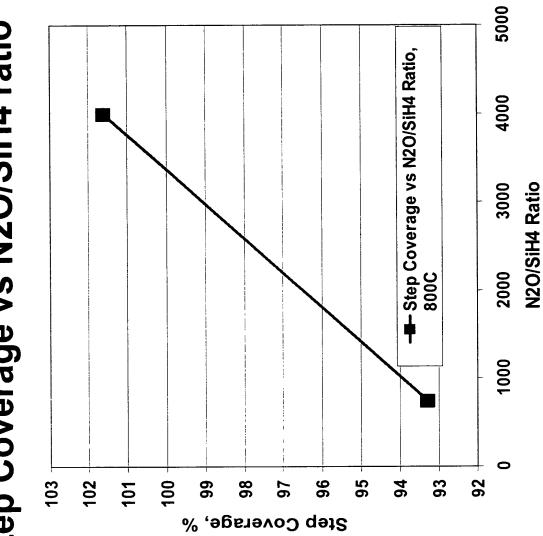


FIG. 14

Step Coverage vs Temperature

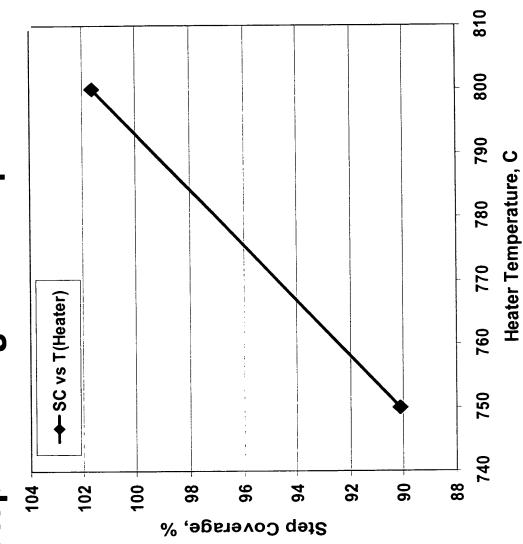


FIG. 15

1_1		60Å	70Å	150Å	1000Å
		Silicon oxide film	Silicon oxide film	Silicon oxide film	Silicon oxide film
2	Pretreatment	Sincon oaide iiiii			
ŀ	Time	10 seconds	10 seconds	10 seconds	10 seconds
	Temperature	750 °C	800 °C	700 °C	800 °C
ŀ	Pressure	200 Torr	200 Torr	200 Torr	200 Torr
	N ₂ O into chamber	500 sccm	1200 sccm	1500 sccm	4000 sccm
	SiH ₄ divert line	1 sccm	2 sccm	2 sccm	20 sccm
	SiH ₄ into chamber	0 sccm	0 sccm	0 sccm	0 sccm
	N ₂ into chamber	5000 sccm	10000 sccm	5000 sccm	10000 sccm
	(carrier for SiH ₄)	3000 300			
	N ₂ into bottom	4000 sccm	8000 sccm	4000 sccm	8000 sccm
	chamber	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,			
3_	Deposition	5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5 5			
	Time	40 seconds	44 seconds	53.2 seconds	75 seconds
	Temperature	750 °C	800 °C	750 °C	750 °C
	Pressure	200 Torr	200 Torr	200 Torr	200 Torr
	N ₂ O into chamber	500 sccm	1200 sccm	1500 sccm	4000 sccm
	SiH ₄ divert line	0 sccm	0 sccm	0 sccm	0 sccm
	SiH ₄ into chamber	1 sccm	2 sccm	2 sccm	20 sccm
	N ₂ into chamber	5000 sccm	10000 sccm	5000 sccm	10000 sccm
	(carrier for SiH ₄)				
	N ₂ into bottom	4000 sccm	8000 sccm	4000 sccm	8000 sccm
	chamber				
Δ			Section Williams And		
•	Posttreatment				
	Time	10 seconds	10 seconds	10 seconds	10 seconds
	Temperature	750 °C	800 °C	750 °C	750 °C
	Pressure	200 Torr	200 Torr	200 Torr	200 Torr
	N ₂ O into chamber	500 sccm	1200 sccm	1500 sccm	4000 sccm
	SiH ₄ divert line	0 sccm	2 sccm	0 sccm	0 sccm
	SiH ₄ into chamber	0 sccm	0 sccm	0 sccm	0 sccm
	N ₂ into chamber	5000 sccm	10000 sccm	5000 sccm	10000 sccm
	(carrier for SiH ₄)				
	N ₂ into bottom	4000 sccm	8000 sccm	4000 sccm	8000 sccm
	chamber				
_					
<u>5</u>	Purge				
	Time	10 seconds	10 seconds	10 seconds	10 seconds
	N ₂ into chamber	5000 sccm	10000 sccm	5000 sccm	10000 sccm
	(carrier for SiH ₄)				-
	N ₂ into bottom	4000 sccm	8000 sccm	4000 sccm	8000 sccm
	chamber	<u> </u>		<u> </u>	

TABLE 1: PARAMETERS FOR MAKING SILICON OXIDE FILMS